Errata

Defect Tolerance in VLSI Circuits: Techniques and Yield Analysis

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Equations (34) and (35) on page 1825 should be corrected as shown below.

$$y_{M+k} = \left(1 + \frac{(M+k)\lambda}{N\alpha}\right)^{-\alpha} \tag{34}$$

and the yield of the chip is

$$Y_{chip} = \sum_{M=N-R}^{N} \sum_{k=0}^{N-M} (-1)^k \binom{N}{M} \binom{N-M}{k} \left(1 + \frac{(M+k)\lambda}{N\alpha}\right)^{-\alpha} \tag{35}$$